

**Supporting Information: Thermal Stability of Titanium Contacts to MoS<sub>2</sub>**

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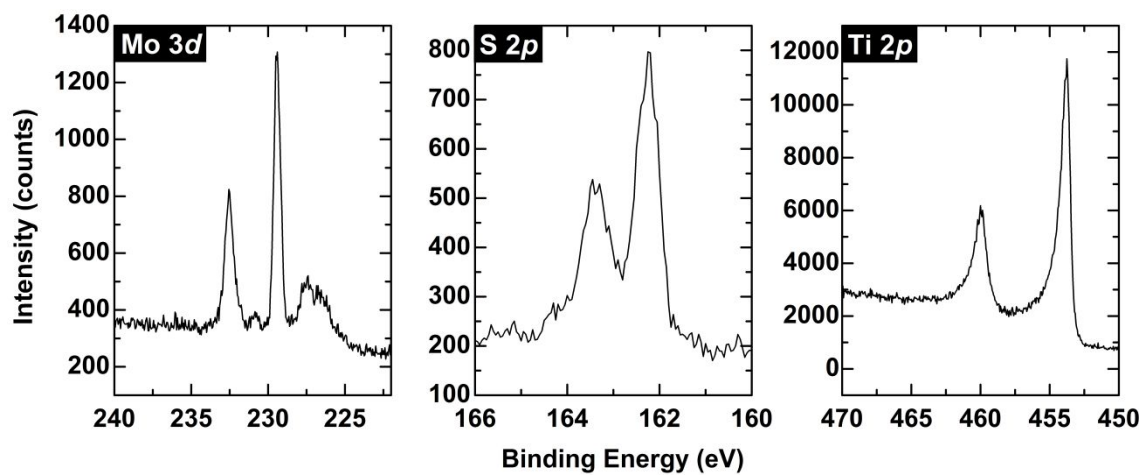
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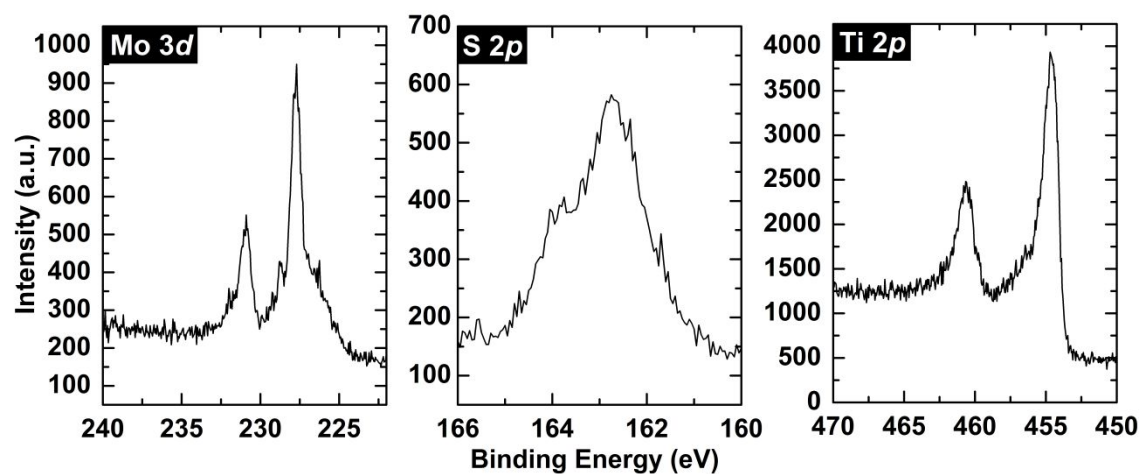
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### XPS of Samples Prepared for TEM



**Figure S1.** XPS spectra of Ti/MoS<sub>2</sub> as-deposited sample corresponding to TEM images shown in text



**Figure S2.** XPS spectra of Ti/MoS<sub>2</sub> sample annealed to 400 °C corresponding to TEM images shown in text